

Search Notes

Application/Control No.

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Examiner

Wayne Langel

Applicant(s)/Patent under
Reexamination

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SEARCHED

Class	Subclass	Date	Examiner
423	239.1	9/23/2004	WAL
423	244.02	9/23/2004	WAL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR